

AP4501M

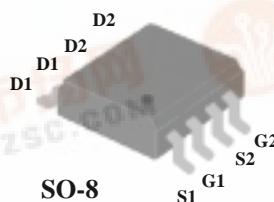
**Advanced Power
Electronics Corp.**

**N AND P-CHANNEL ENHANCEMENT
MODE POWER MOSFET**

▼ Simple Drive Requirement

▼ Low On-resistance

▼ Fast Switching

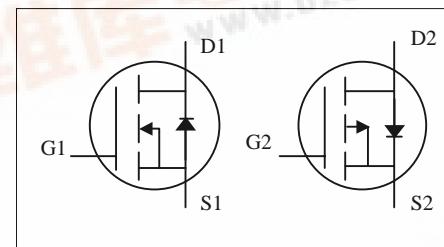


Description

The Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SO-8 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

N-CH	BV_{DSS}	30V
	$R_{DS(ON)}$	28mΩ
	I_D	7A
P-CH	BV_{DSS}	-30V
	$R_{DS(ON)}$	50mΩ
	I_D	-5.3A



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-channel	P-channel	
V_{DS}	Drain-Source Voltage	30	-30	V
V_{GS}	Gate-Source Voltage	± 20	± 20	V
$I_D @ T_A=25^\circ C$	Continuous Drain Current ³	7	-5.3	A
$I_D @ T_A=70^\circ C$	Continuous Drain Current ³	5.8	-4.7	A
I_{DM}	Pulsed Drain Current ¹	20	-20	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation	2		W
	Linear Derating Factor	0.016		W/°C
T_{STG}	Storage Temperature Range	-55 to 150		°C
T_J	Operating Junction Temperature Range	-55 to 150		°C

Thermal Data

Symbol	Parameter	Value	Unit
$R_{thj-amb}$	Thermal Resistance Junction-ambient ³	Max. 62.5	°C/W



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N-CH Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=250\mu\text{A}$	30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_{\text{D}}=1\text{mA}$	-	0.02	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_{\text{D}}=7\text{A}$	-	-	28	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_{\text{D}}=5\text{A}$	-	-	42	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_{\text{D}}=7\text{A}$	-	13	-	S
I_{DSS}	Drain-Source Leakage Current ($T_j=25^\circ\text{C}$)	$V_{\text{DS}}=30\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	1	uA
	Drain-Source Leakage Current ($T_j=70^\circ\text{C}$)	$V_{\text{DS}}=24\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	25	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=7\text{A}$	-	8.4	-	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=24\text{V}$	-	2.1	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	4.7	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=15\text{V}$	-	6	-	ns
t_r	Rise Time	$I_{\text{D}}=1\text{A}$	-	5.2	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega$, $V_{\text{GS}}=10\text{V}$	-	18.8	-	ns
t_f	Fall Time	$R_D=15\Omega$	-	4.4	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	645	-	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	150	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	95	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
I_s	Continuous Source Current (Body Diode)	$V_D=V_G=0\text{V}$, $V_S=1.2\text{V}$	-	-	1.67	A
V_{SD}	Forward On Voltage ²	$T_j=25^\circ\text{C}$, $I_s=7\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.2	V

**P-CH Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_{\text{D}}=-1\text{mA}$	-	-0.028	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-5.3\text{A}$	-	-	50	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-4.2\text{A}$	-	-	90	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-5.3\text{A}$	-	8.5	-	S
I_{DSS}	Drain-Source Leakage Current ($T=25^\circ\text{C}$)	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	uA
	Drain-Source Leakage Current ($T=70^\circ\text{C}$)	$V_{\text{DS}}=-24\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-25	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=-5.3\text{A}$	-	20	-	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-15\text{V}$	-	3.5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-10\text{V}$	-	2	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=-15\text{V}$	-	12	-	ns
t_r	Rise Time	$I_{\text{D}}=-1\text{A}$	-	20	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=6\Omega, V_{\text{GS}}=-10\text{V}$	-	45	-	ns
t_f	Fall Time	$R_D=15\Omega$	-	27	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	790	-	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=-15\text{V}$	-	440	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	120	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
I_S	Continuous Source Current (Body Diode)	$V_D=V_G=0\text{V}, V_S=-1.2\text{V}$	-	-	-1.67	A
V_{SD}	Forward On Voltage ²	$T_j=25^\circ\text{C}, I_S=-2.6\text{A}, V_{\text{GS}}=0\text{V}$	-	-	-1.2	V

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.
- 3.Surface mounted on 1 in² copper pad of FR4 board ; $135^\circ\text{C}/\text{W}$ when mounted on Min. copper pad.

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N-Channel

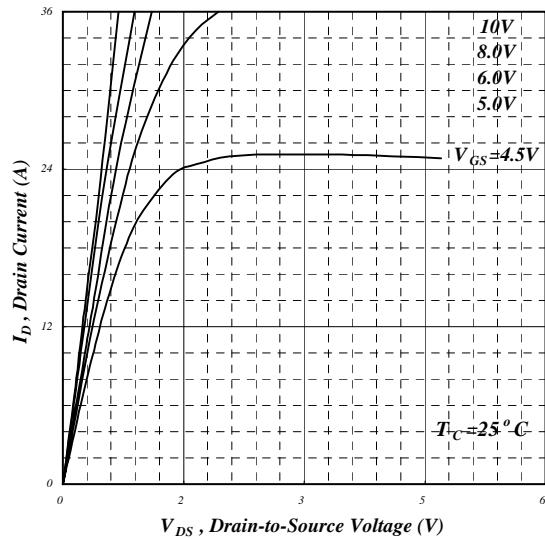


Fig 1. Typical Output Characteristics

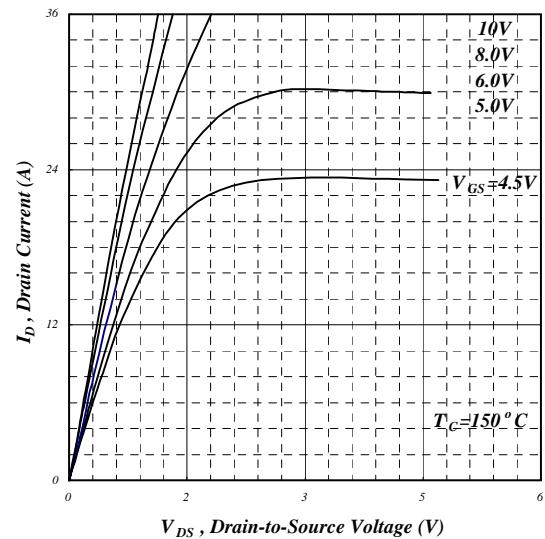


Fig 2. Typical Output Characteristics

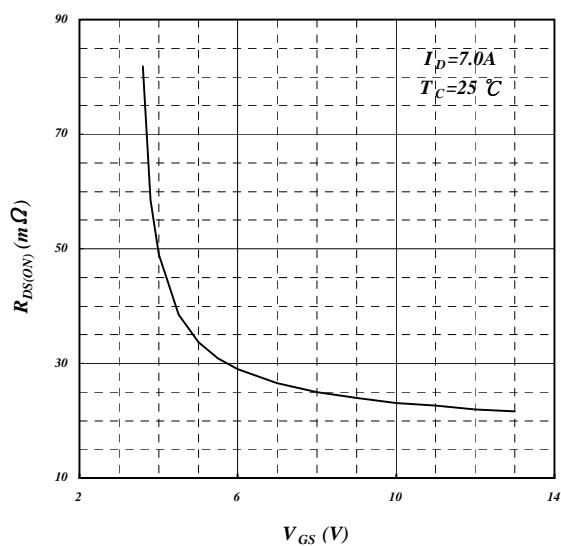


Fig 3. On-Resistance v.s. Gate Voltage

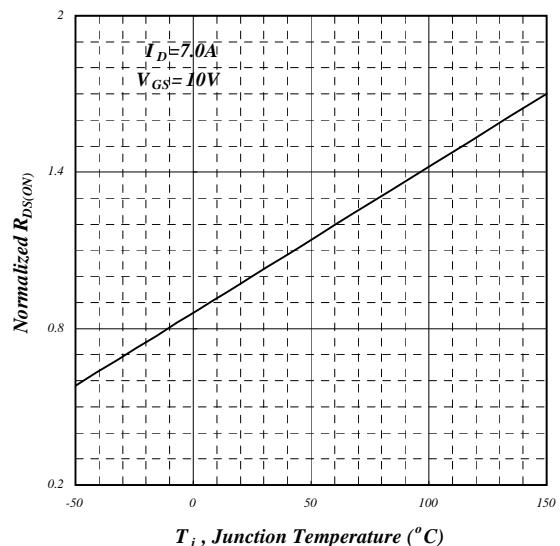
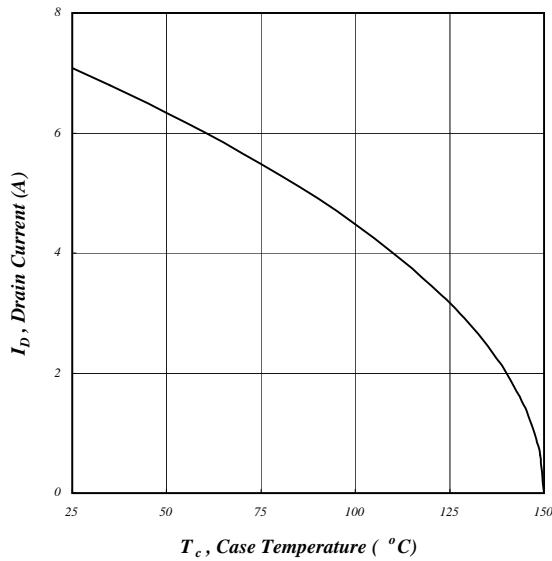


Fig 4. Normalized On-Resistance v.s. Junction Temperature



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N-Channel



**Fig 5. Maximum Drain Current v.s.
Case Temperature**

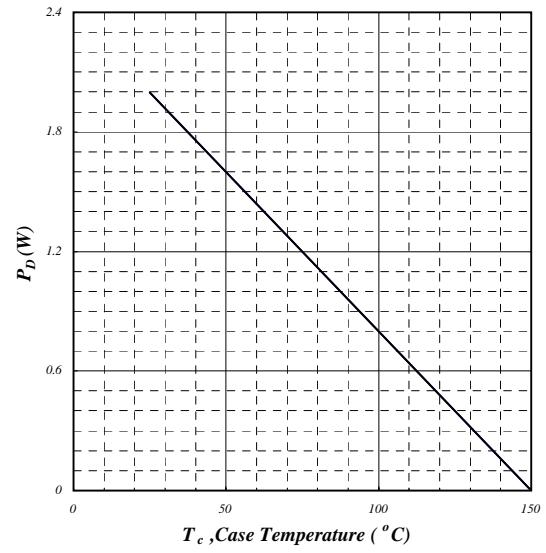


Fig 6. Typical Power Dissipation

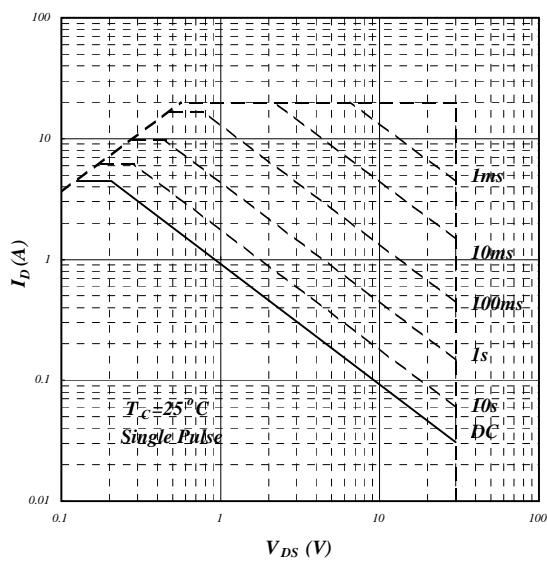


Fig 7. Maximum Safe Operating Area

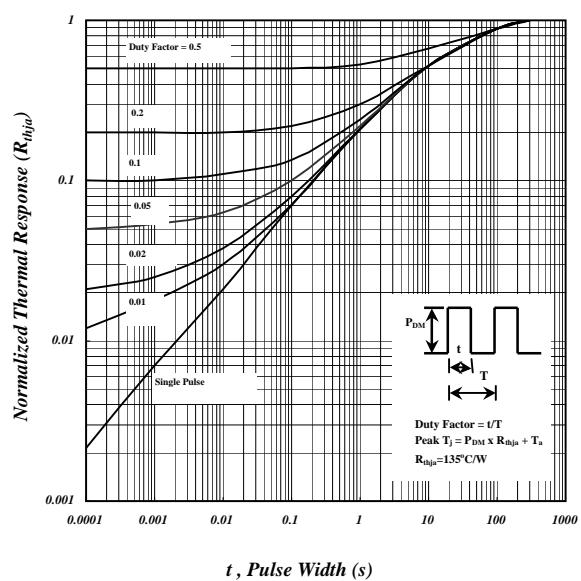


Fig 8. Effective Transient Thermal Impedance

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N-Channel

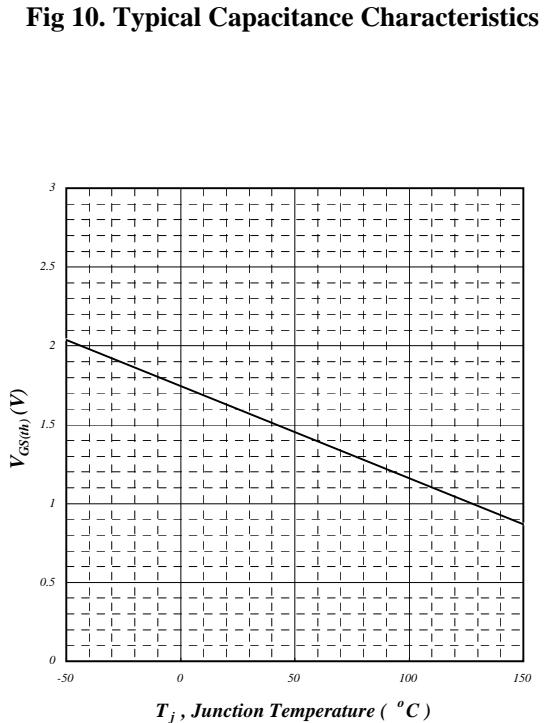
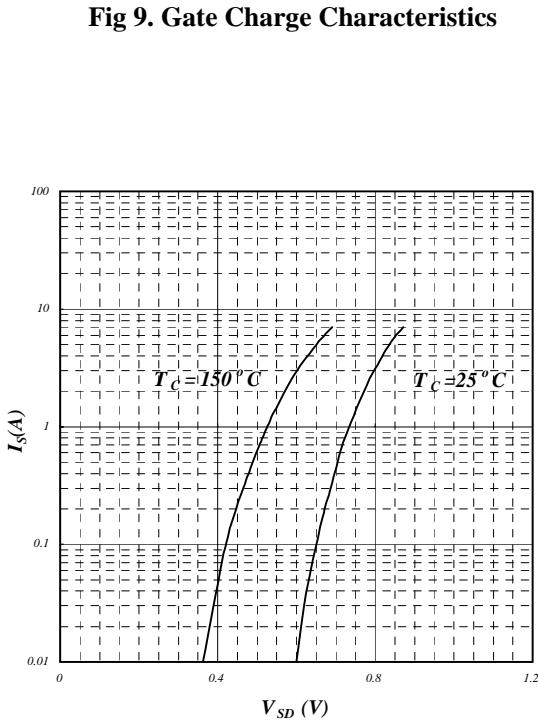
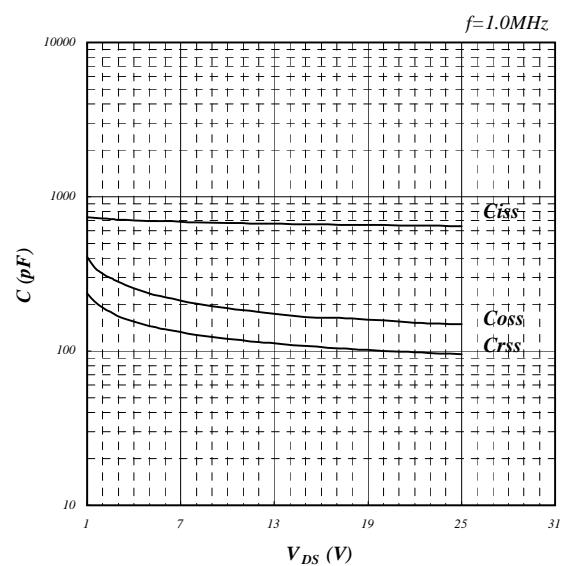
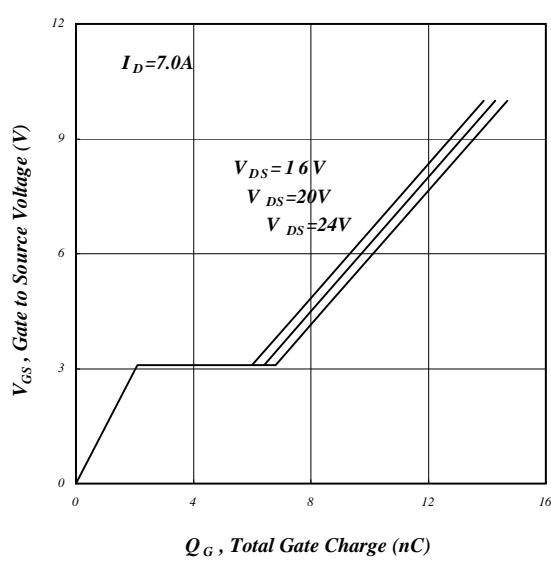


Fig 11. Forward Characteristic of Reverse Diode

Fig 12. Gate Threshold Voltage v.s. Junction Temperature

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N-Channel

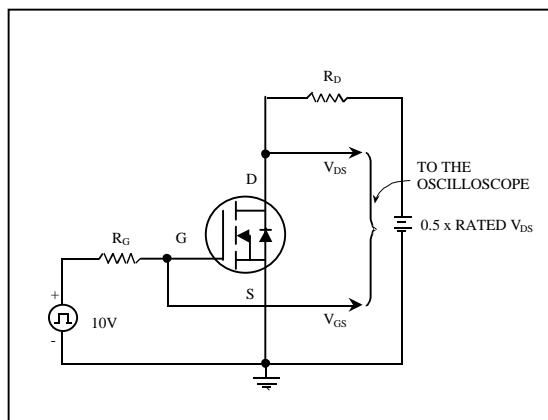


Fig 13. Switching Time Circuit

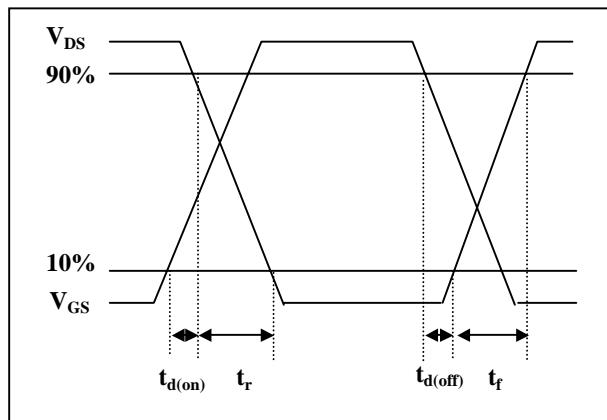


Fig 14. Switching Time Waveform

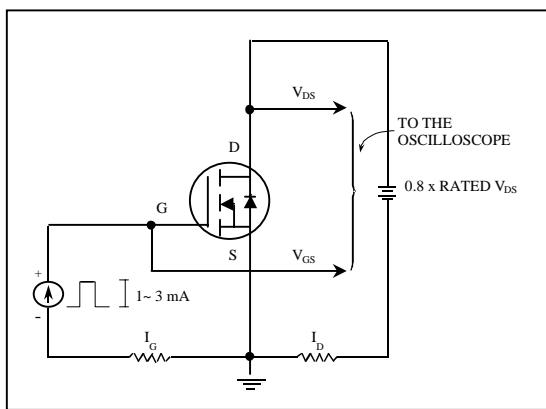


Fig 15. Gate Charge Circuit

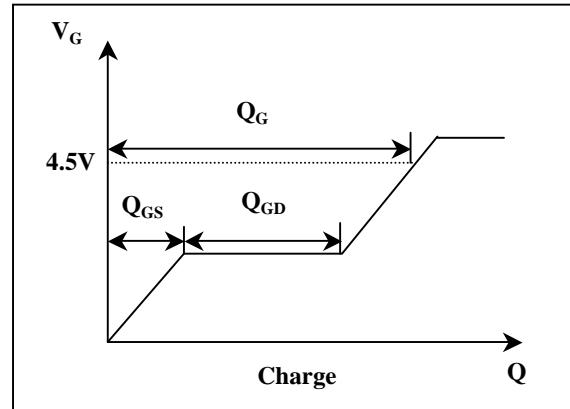


Fig 16. Gate Charge Waveform

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P-Channel

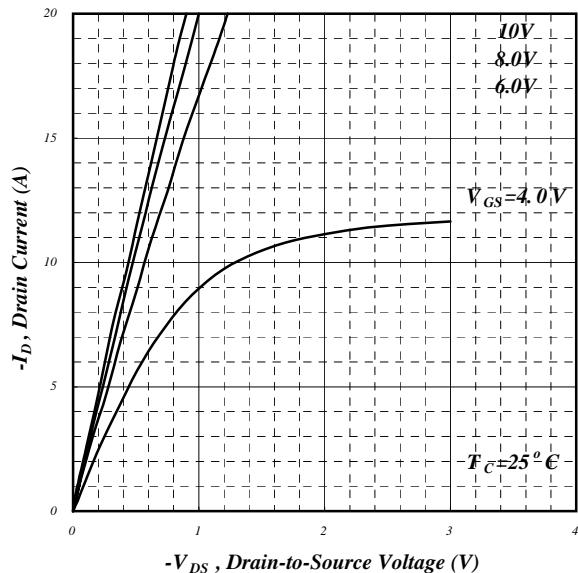


Fig 1. Typical Output Characteristics

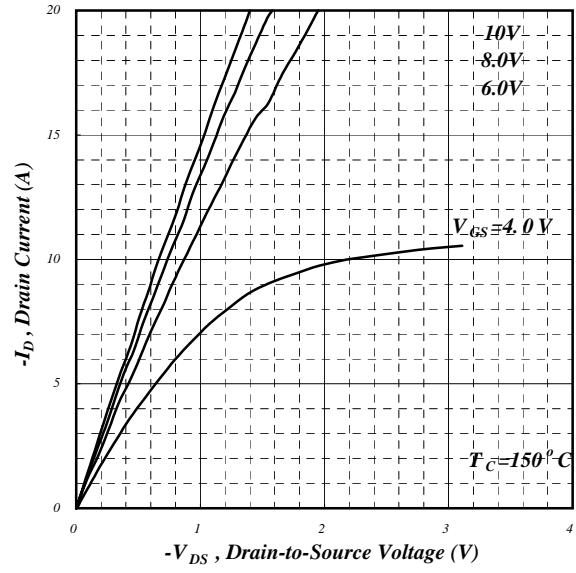


Fig 2. Typical Output Characteristics

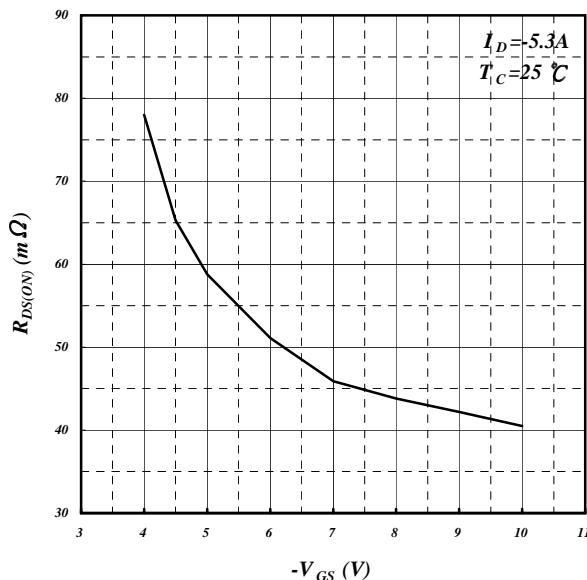


Fig 3. On-Resistance v.s. Gate Voltage

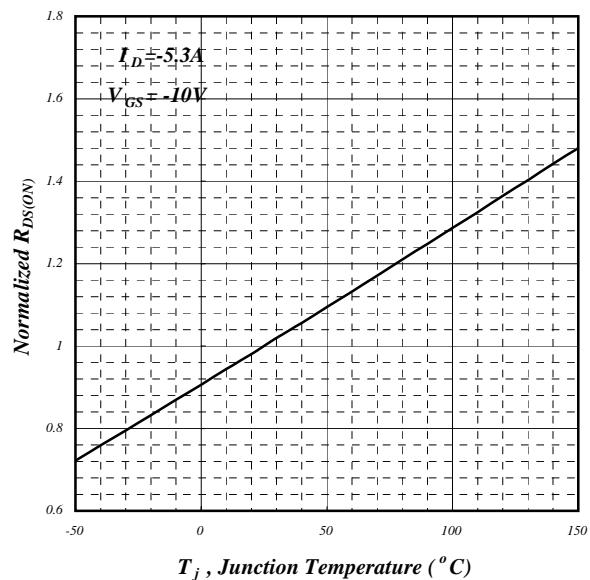
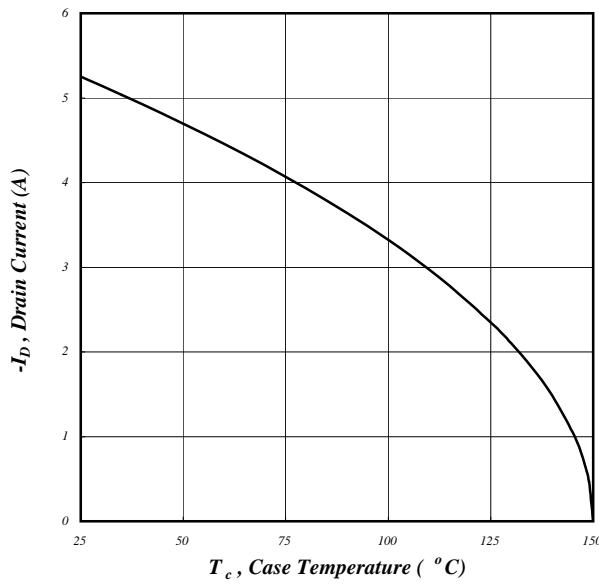


Fig 4. Normalized On-Resistance v.s. Junction Temperature



P-Channel



**Fig 5. Maximum Drain Current v.s.
Case Temperature**

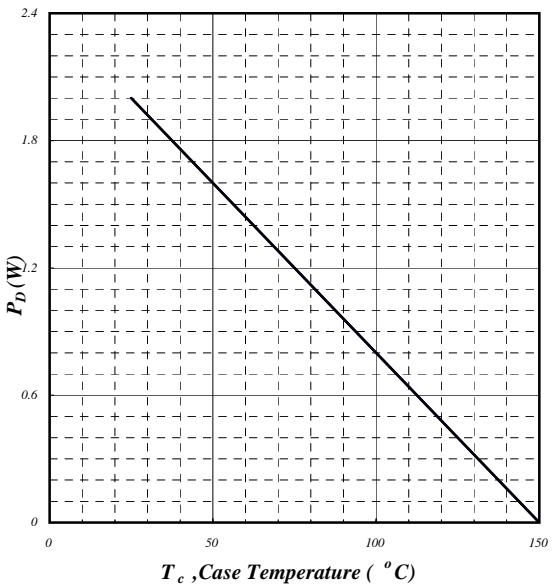


Fig 6. Typical Power Dissipation

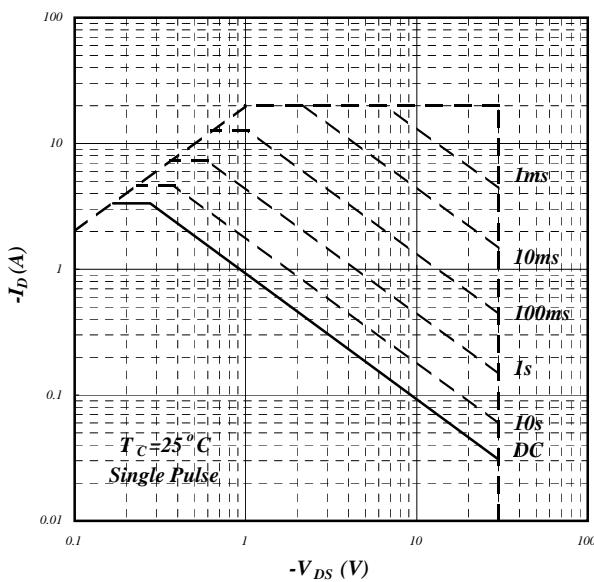


Fig 7. Maximum Safe Operating Area

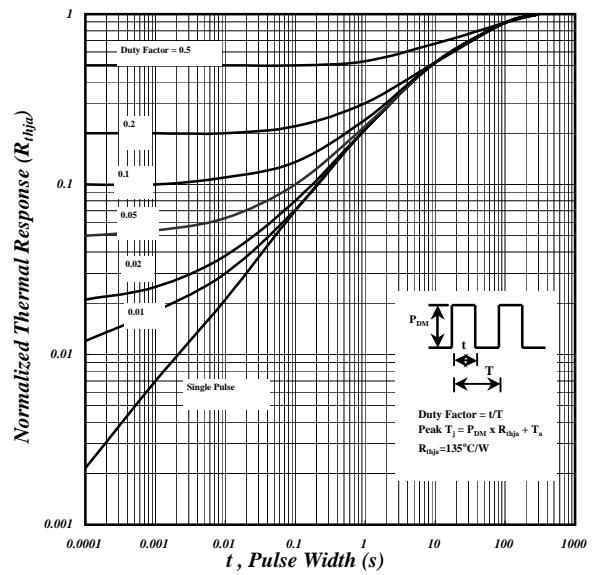


Fig 8. Effective Transient Thermal Impedance



P-Channel

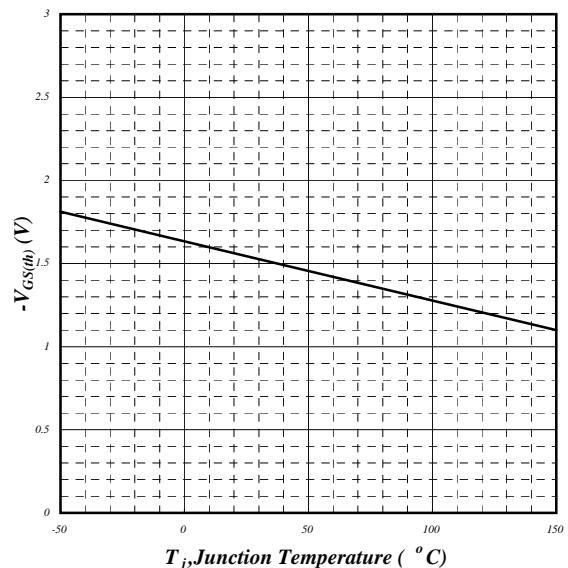
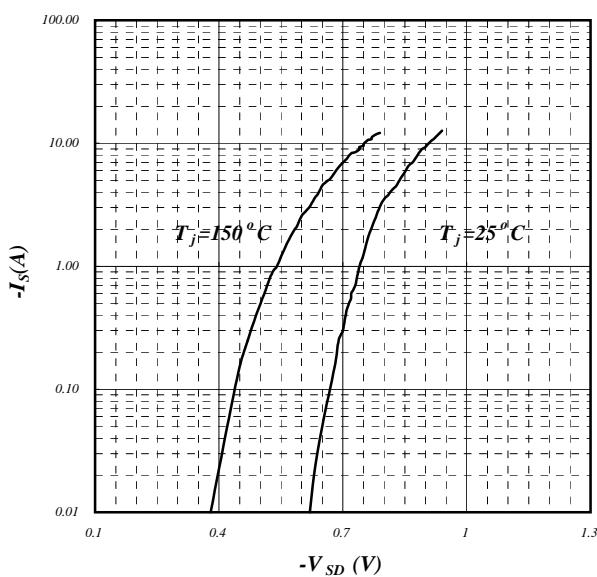
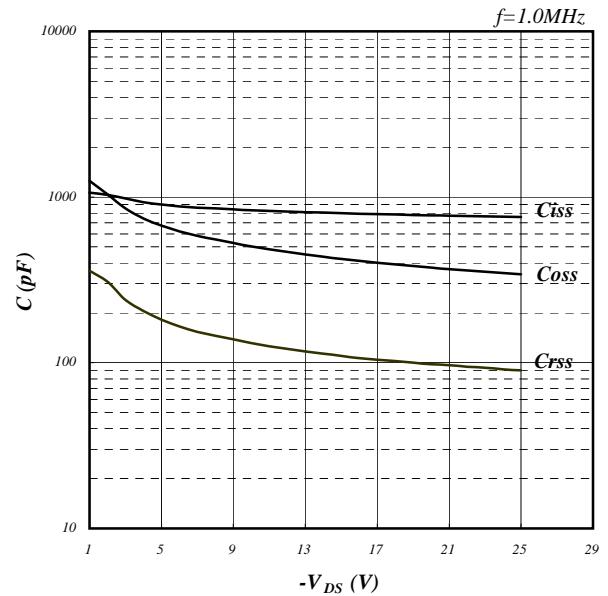
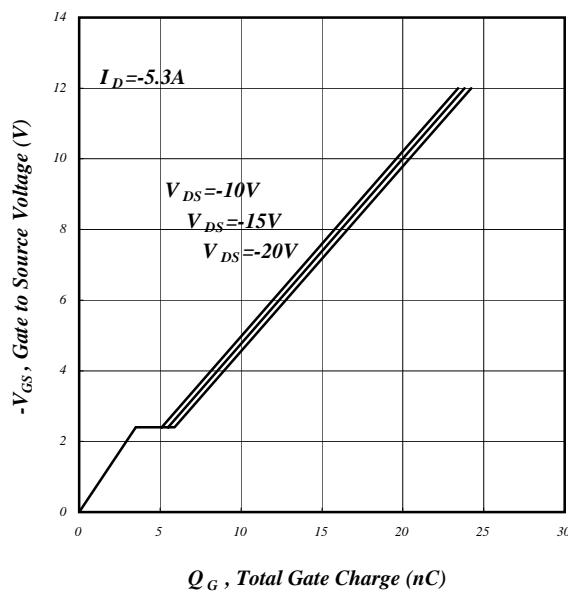
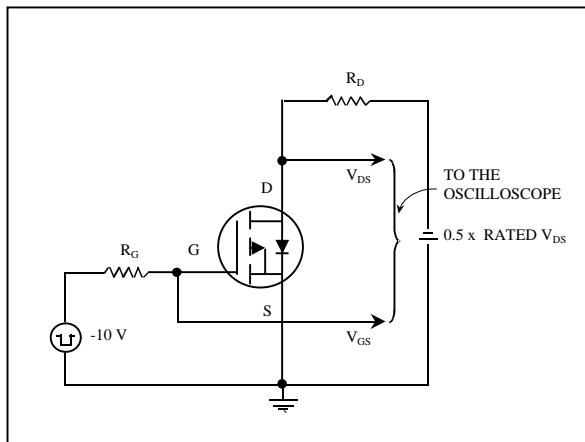
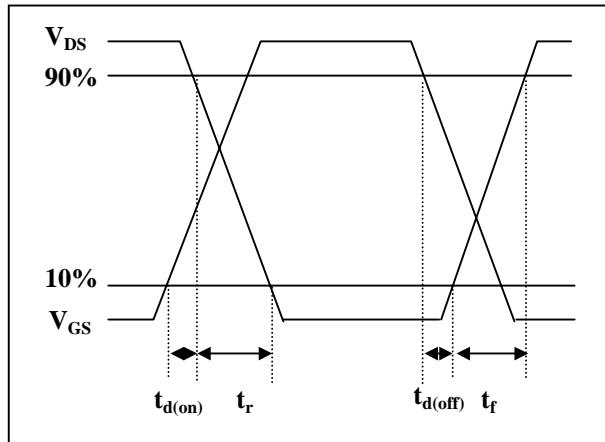
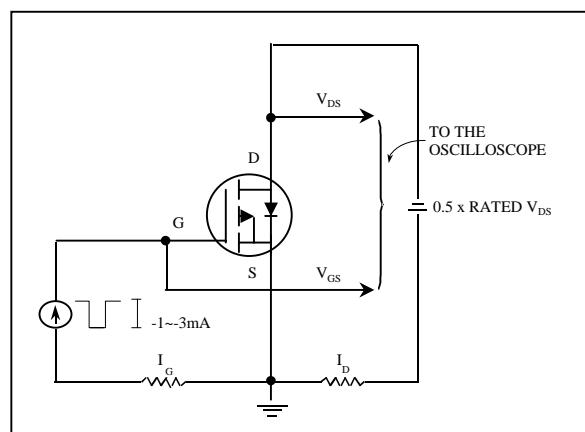
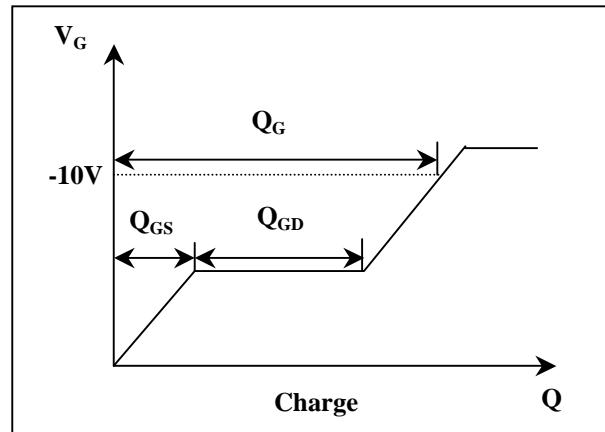


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Fig 12. Gate Threshold Voltage v.s. Junction Temperature

**P-Channel****Fig 13. Switching Time Circuit****Fig 14. Switching Time Waveform****Fig 15. Gate Charge Circuit****Fig 16. Gate Charge Waveform**